



6/11/2012

**PRODUCT RELIABILITY REPORT
FOR**

MAX31826

Maxim Integrated Products

**4401 South Beltwood Parkway
Dallas, TX 75244-3292**

Prepared by:

**Don Lipps
Manager, Reliability Engineering
Maxim Integrated Products
4401 South Beltwood Pkwy.
Dallas, TX 75244-3292
Email: don.lipps@maxim-ic.com
ph: 972-371-3739**

Conclusion:

The following qualification successfully meets the quality and reliability standards required of all Maxim products:

MAX31826

In addition, Maxim's continuous reliability monitor program ensures that all outgoing product will continue to meet Maxim's quality and reliability standards. The current status of the reliability monitor program can be viewed at <http://www.maxim-ic.com/TechSupport/dsreliability.html>.

Device Description:

A description of this device can be found in the product data sheet. You can find the product data sheet at http://dbserv.maxim-ic.com/l_datasheet3.cfm.

Reliability Derating:

The Arrhenius model will be used to determine the acceleration factor for failure mechanisms that are temperature accelerated.

$$AfT = \exp((Ea/k) * (1/Tu - 1/Ts)) = tu/ts$$

AfT = Acceleration factor due to Temperature
tu = Time at use temperature (e.g. 55°C)
ts = Time at stress temperature (e.g. 125°C)
k = Boltzmann's Constant (8.617 x 10⁻⁵ eV/°K)
Tu = Temperature at Use (°K)
Ts = Temperature at Stress (°K)
Ea = Activation Energy (e.g. 0.7 ev)

The activation energy of the failure mechanism is derived from either internal studies or industry accepted standards, or activation energy of 0.7ev will be used whenever actual failure mechanisms or their activation energies are unknown. All deratings will be done from the stress ambient temperature to the use ambient temperature.

An exponential model will be used to determine the acceleration factor for failure mechanisms, which are voltage accelerated.

$$AfV = \exp(B * (Vs - Vu))$$

AfV = Acceleration factor due to Voltage
Vs = Stress Voltage (e.g. 7.0 volts)
Vu = Maximum Operating Voltage (e.g. 5.5 volts)
B = Constant related to failure mechanism type (e.g. 1.0, 2.4, 2.7, etc.)

The Constant, B, related to the failure mechanism is derived from either internal studies or industry accepted standards, or a B of 1.0 will be used whenever actual failure mechanisms or their B are unknown. All deratings will be done from the stress voltage to the maximum operating voltage. Failure rate data from the operating life test is reported using a Chi-Squared statistical model at the 60% or 90% confidence level (Cf).

The failure rate, Fr, is related to the acceleration during life test by:

$$Fr = X / (ts * AfV * AfT * N * 2)$$

X = Chi-Sq statistical upper limit
N = Life test sample size

Failure Rates are reported in FITs (Failures in Time) or MTTF (Mean Time To Failure). The FIT rate is related to MTTF by:

$$\text{MTTF} = 1/\text{Fr}$$

NOTE: MTTF is frequently used interchangeably with MTBF.

The calculated failure rate for this device/process is:

FAILURE RATE: **MTTF (YRS):** **99702** **FITS:** **1.1**
DEVICE HOURS: **800278339** **FAILS:** **0**

Only data from Operating Life or similar stresses are used for this calculation.

The parameters used to calculate this failure rate are as follows:

Cf: 60% **Ea: 0.7** **B: 0** **Tu: 25** °C **Vu: 3.6** Volts

The reliability data follows. At the start of this data is the device information. The next section is the detailed reliability data for each stress. The reliability data section includes the latest data available and may contain some generic data. **Bold** Product Number denotes specific product data.

Device Information:

Process: SA E35W-0.5um, 5V CMOS with embedded Array EEPROM, embedded RSE EEPROM, 18V CMOS, VNP, P2-P1 Cap, LVMOSCAP, HVMOSCAP, Varactor Cap, NTC poly R's, 3LM, M3 Laser Fuses
 Passivation: TEOS Oxide-Nitride Passivation
 Die Size: 63 x 89
 Number of Transistors: 33923
 Interconnect: Aluminum / 0.5% Copper
 Gate Oxide Thickness: 120 Å

ESD HBM

DESCRIPTION	DATE	CODE/PRODUCT/LOT	CONDITION	READPOIN	QTY	FAILS	FA#
ESD SENSITIVITY	1205	MAX31826	ZD272115AB JESD22-A114 HBM 500 VOLTS	1	PUL'S	5	0
ESD SENSITIVITY	1205	MAX31826	ZD272115AB JESD22-A114 HBM 1000 VOLTS	1	PUL'S	5	0
ESD SENSITIVITY	1205	MAX31826	ZD272115AB JESD22-A114 HBM 1500 VOLTS	1	PUL'S	5	0
ESD SENSITIVITY	1205	MAX31826	ZD272115AB JESD22-A114 HBM 2000 VOLTS	1	PUL'S	5	0
ESD SENSITIVITY	1205	MAX31826	ZD272115AB JESD22-A114 HBM 2500 VOLTS	1	PUL'S	5	0
Total:						0	

LATCH-UP

DESCRIPTION	DATE	CODE/PRODUCT/LOT	CONDITION	READPOIN	QTY	FAILS	FA#
LATCH-UP I	1205	MAX31826	ZD272115AB JESD78A, I-TEST 25C 100mA			6	0
LATCH-UP I	1205	MAX31826	ZD272115AB JESD78A, I-TEST 25C 250mA			6	0
LATCH-UP V	1205	MAX31826	ZD272115AB JESD78A, V-SUPPLY TEST 25C			6	0
Total:						0	

OPERATING LIFE

DESCRIPTION	DATE	CODE/PRODUCT/LOT	CONDITION	READPOIN	QTY	FAILS	FA#
HIGH TEMP OP LIFE	0845	DS2431	WJ943331AB 125C, 5.25 VOLTS	1000 HRS	77	0	
HIGH TEMP OP LIFE	0845	DS2431	WJ943238Q 125C, 5.25 VOLTS	1000 HRS	77	0	
HIGH TEMP OP LIFE	0846	DS28EC20	WJ941331D 125C, 5.25 VOLTS	1000 HRS	77	0	
HIGH TEMP OP LIFE	0846	DS28EC20	WJ942984PB 125C, 5.25 VOLTS	1000 HRS	77	0	
HIGH TEMP OP LIFE	0846	DS28EC20	WJ943330BB 125C, 5.25 VOLTS	1000 HRS	77	0	
HIGH TEMP OP LIFE	0846	DS28EC20	WJ942984PB 125C, 5.25 VOLTS	408 HRS	80	0	
HIGH TEMP OP LIFE	0848	DS2431	WJ943235BB 125C, 5.25 VOLTS	1000 HRS	77	0	
HIGH TEMP OP LIFE	0951	DS2430A	WH048838A 125C, 5.25 VOLTS	192 HRS	50	0	
HIGH TEMP OP LIFE	1004	MAX66140	WJ050342AB 125C, 3.3 VOLTS	192 HRS	45	0	
HIGH TEMP OP LIFE	1009	DS1624	WJ048844BB 125C, 5.5 VOLTS	192 HRS	77	0	
HIGH TEMP OP LIFE	1013	DS2431	WJ052466AB 150C, 5.25 VOLTS	408 HRS	50	0	
HIGH TEMP OP LIFE	1013	DS2431	WJ052268AB 150C, 5.25 VOLTS	408 HRS	50	0	
HIGH TEMP OP LIFE	1014	DS2431	WJ052527AB 150C, 5.25 VOLTS	408 HRS	50	0	
HIGH TEMP OP LIFE	1039	MAX31722	ZJ148849DB 125C, 3.7V (PSA)	192 HRS	48	0	
HIGH TEMP OP LIFE	1110	DS2431	FH163875AC 125C, 5.25 VOLTS	1000 HRS	77	0	
HIGH TEMP OP LIFE	1125	DSKCP60	ZD167395BB 125C, 5.5 VOLTS	192 HRS	77	0	
HIGH TEMP OP LIFE	1205	MAX31826	ZD272115AB 125C, 3.6 VOLTS	192 HRS	80	0	

Total: 0

FAILURE RATE: MTTF (YRS): 99702 FITS: 1.1
DEVICE HOURS: 800278339 FAILS: 0